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Guohai Situ
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Introduction

This volume contains papers presented during the 2019 International Conference on Optical Instrument and Technology (OIT 2019) at the topical meeting of Optoelectronic Imaging/Spectroscopy and Signal Processing Technology. The focus of this meeting was especially directed to advancements in this field and related areas. The extended scope was honored by a great response to our call for papers. Scientists and engineers, in particular from China, offered more than 50 papers.

This enormous response demanded a strong review of the papers to select the best out of the overwhelming number of excellent papers. The strong limitation of the number of papers which could be presented orally and discussed effectively during a one-and-a-half day meeting without holding parallel sessions was again an important factor. The classification of all accepted papers into the five topical sessions listed above was also very difficult and it often required compromises. We hope that our decision will be accepted by the audience.

The editors would like to express their thanks to the international program committee for helping us to find a good solution to finalize the meeting. We would also like to thank all the authors who spent a lot of time and effort in the preparation of their papers. Our appreciation also goes to Prof. Liquan Dong and Mrs. Cuiling Li, and all the local staff from Beijing Institute of Technology (China). Without their help, it would not have been possible to make the meeting so successful.

Guohai Situ
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